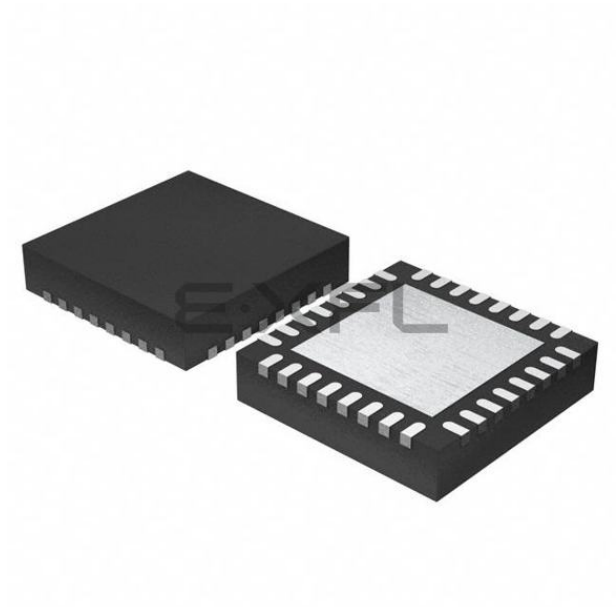

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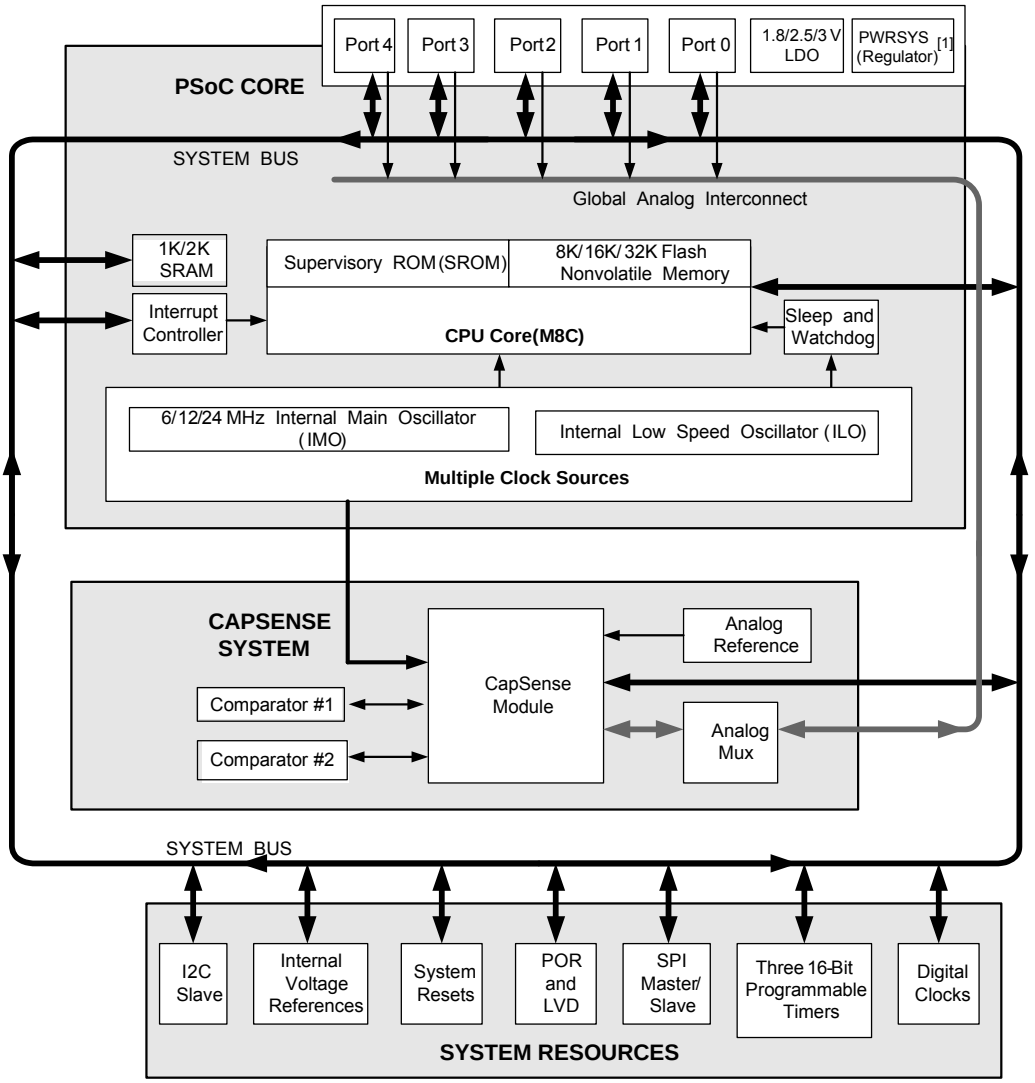
What Are Embedded - Microcontrollers - Application Specific?

Application-specific microcontrollers are engineered to

Details	
Product Status	Obsolete
Applications	Capacitive Sensing
Core Processor	M8C
Program Memory Type	FLASH (16kB)
Controller Series	CY8C20xx7/S
RAM Size	2K x 8
Interface	I²C, SPI
Number of I/O	29
Voltage - Supply	1.71V ~ 5.5V
Operating Temperature	-40°C ~ 85°C
Mounting Type	Surface Mount
Package / Case	32-UFQFN Exposed Pad
Supplier Device Package	32-QFN (5x5)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/cy8c20447-24lqxi

Logic Block Diagram



Note
1. Internal voltage regulator for internal circuitry

Designing with PSoC Designer

The PSoC development process can be summarized in the following four steps:

1. Select User Modules
2. Configure User Modules
3. Organize and Connect
4. Generate and Verify

Select Components

PSoC Designer provides a library of pre-built, pre-tested hardware peripheral components called “user modules”. User modules make selecting and implementing peripheral devices, both analog and digital, simple.

Configure Components

Each of the User Modules you select establishes the basic register settings that implement the selected function. They also provide parameters and properties that allow you to tailor their precise configuration to your particular application. The user module parameters permit you to establish the pulse width and duty cycle. Configure the parameters and properties to correspond to your chosen application. Enter values directly or by selecting values from drop-down menus. All the user modules are documented in datasheets that may be viewed directly in PSoC Designer or on the Cypress website. These user module datasheets explain the internal operation of the User Module and provide performance specifications. Each datasheet describes the use of each user module parameter, and other information you may need to successfully implement your design.

Organize and Connect

You build signal chains at the chip level by interconnecting user modules to each other and the I/O pins. You perform the selection, configuration, and routing so that you have complete control over all on-chip resources.

Generate, Verify, and Debug

When you are ready to test the hardware configuration or move on to developing code for the project, you perform the “Generate Configuration Files” step. This causes PSoC Designer to generate source code that automatically configures the device to your specification and provides the software for the system. The generated code provides application programming interfaces (APIs) with high-level functions to control and respond to hardware events at run time and interrupt service routines that you can adapt as needed.

A complete code development environment allows you to develop and customize your applications in C, assembly language, or both.

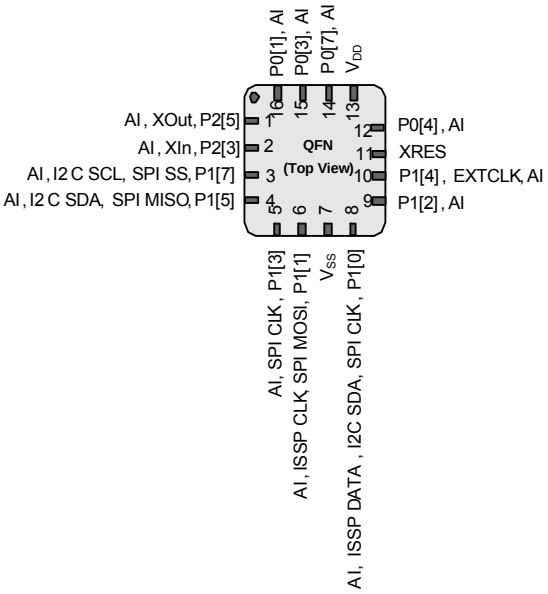
16-pin QFN (10 Sensing Inputs)[8]

Table 2. Pin Definitions – CY8C20237, CY8C20247/S [9]

Pin No.	Type		Name	Description
	Digital	Analog		
1	I/O	I	P2[5]	Crystal output (XOut)
2	I/O	I	P2[3]	Crystal input (XIn)
3	IOHR	I	P1[7]	I^2C SCL, SPI SS
4	IOHR	I	P1[5]	I^2C SDA, SPI MISO
5	IOHR	I	P1[3]	SPI CLK
6	IOHR	I	P1[1]	ISSP CLK[10], I^2C SCL, SPI MOSI
7	Power		V_{SS}	Ground connection[13]
8	IOHR	I	P1[0]	ISSP DATA[10], I^2C SDA, SPI CLK[11]
9	IOHR	I	P1[2]	Driven Shield Output (optional)
10	IOHR	I	P1[4]	Optional external clock (EXTCLK)
11	Input		XRES	Active high external reset with internal pull-down[12]
12	IOH	I	P0[4]	
13	Power		V_{DD}	Supply voltage
14	IOH	I	P0[7]	
15	IOH	I	P0[3]	Integrating input
16	IOH	I	P0[1]	Integrating input

LEGEND A = Analog, I = Input, O = Output, OH = 5 mA High Output Drive, R = Regulated Output.

Figure 3. CY8C20237, CY8C20247/S Device



Notes
8. No center pad.
9. 13 GPIOs = 10 pins for capacitive sensing+2 pins for I^2C + 1 pin for modulator capacitor.
10. On power-up, the SDA(P1[0]) drives a strong high for 256 sleep clock cycles and drives resistive low for the next 256 sleep clock cycles. The SCL(P1[1]) line drives resistive low for 512 sleep clock cycles and both the pins transition to high impedance state. On reset, after XRES de-asserts, the SDA and the SCL lines drive resistive low for 8 sleep clock cycles and transition to high impedance state. Hence, during power-up or reset event, P1[1] and P1[0] may disturb the I^2C bus. Use alternate pins if you encounter issues.
11. Alternate SPI clock.
12. The internal pull down is 5KOhm.
13. All VSS pins should be brought out to one common GND plane.

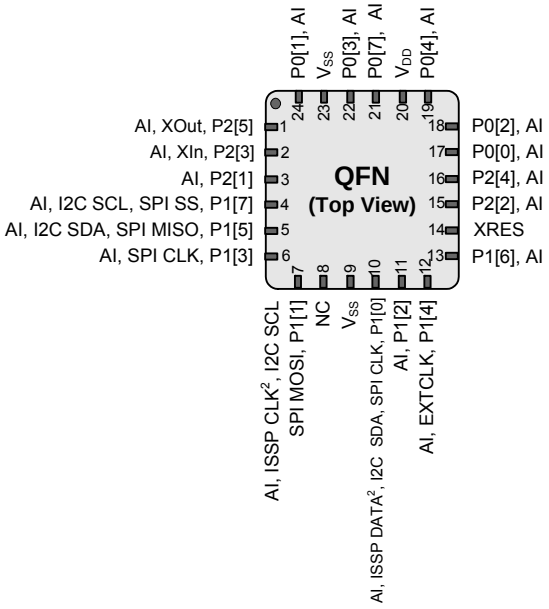
24-pin QFN (16 Sensing Inputs)[14]

Table 3. Pin Definitions – CY8C20337, CY8C20347/S [15]

Pin No.	Type		Name	Description
	Digital	Analog		
1	I/O	I	P2[5]	Crystal output (XOut)
2	I/O	I	P2[3]	Crystal input (XIn)
3	I/O	I	P2[1]	
4	IOHR	I	P1[7]	I^2C SCL, SPI SS
5	IOHR	I	P1[5]	I^2C SDA, SPI MISO
6	IOHR	I	P1[3]	SPI CLK
7	IOHR	I	P1[1]	ISSP CLK[16], I^2C SCL, SPI MOSI
8			NC	No connection
9	Power		V_{SS}	Ground connection[19]
10	IOHR	I	P1[0]	ISSP DATA[16], I^2C SDA, SPI CLK[17]
11	IOHR	I	P1[2]	Driven Shield Output (optional)
12	IOHR	I	P1[4]	Optional external clock input (EXTCLK)
13	IOHR	I	P1[6]	
14	Input		XRES	Active high external reset with internal pull-down[18]
15	I/O	I	P2[2]	Driven Shield Output (optional)
16	I/O	I	P2[4]	Driven Shield Output (optional)
17	IOH	I	P0[0]	Driven Shield Output (optional)
18	IOH	I	P0[2]	Driven Shield Output (optional)
19	IOH	I	P0[4]	
20	Power		V_{DD}	Supply voltage
21	IOH	I	P0[7]	
22	IOH	I	P0[3]	Integrating input
23	Power		V_{SS}	Ground connection[19]
24	IOH	I	P0[1]	Integrating input
CP	Power		V_{SS}	Center pad must be connected to ground

LEGEND A = Analog, I = Input, O = Output, OH = 5 mA High Output Drive, R = Regulated Output.

Figure 4. CY8C20337, CY8C20347/S Device



Notes

14. The center pad (CP) on the QFN package must be connected to ground (V_{SS}) for best mechanical, thermal, and electrical performance. If not connected to ground, it must be electrically floated and not connected to any other signal.
15. 19 GPIOs = 16 pins for capacitive sensing+2 pins for I^2C + 1 pin for modulator capacitor.
16. On power-up, the SDA(P1[0]) drives a strong high for 256 sleep clock cycles and drives resistive low for the next 256 sleep clock cycles. The SCL(P1[1]) line drives resistive low for 512 sleep clock cycles and both the pins transition to high impedance state. On reset, after XRES de-asserts, the SDA and the SCL lines drive resistive low for 8 sleep clock cycles and transition to high impedance state. Hence, during power-up or reset event, P1[1] and P1[0] may disturb the I^2C bus. Use alternate pins if you encounter issues.
17. Alternate SPI clock.
18. The internal pull down is 5KOhm.
19. All VSS pins should be brought out to one common GND plane.

30-ball WLCSP (24 Sensing Inputs)

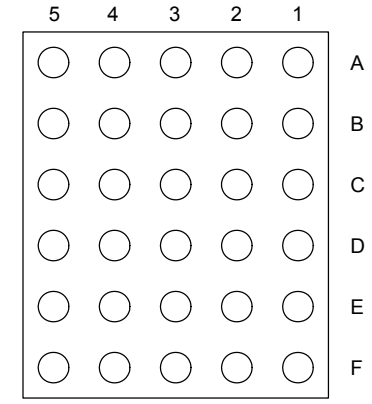
Table 4. Pin Definitions – CY8C20767, CY8C20747 30-ball Part Pinout (WLCSP) [20]

Pin No.	Type		Name	Description
	Digital	Analog		
A1	IOH	I	P0[2]	Driven Shield Output (optional)
A2	IOH	I	P0[6]	
A3	Power		V_{DD}	Supply voltage
A4	IOH	I	P0[1]	Integrating Input
A5	I/O	I	P2[7]	
B1	I/O	I	P4[2]	
B2	IOH	I	P0[0]	Driven Shield Output (optional)
B3	IOH	I	P0[4]	
B4	IOH	I	P0[3]	Integrating Input
B5	I/O	I	P2[5]	Crystal Output (Xout)
C1	I/O	I	P2[2]	Driven Shield Output (optional)
C2	I/O	I	P2[4]	Driven Shield Output (optional)
C3	I/O	I	P0[7]	
C4	IOH	I	P3[2]	
C5	I/O	I	P2[3]	Crystal Input (Xin)
D1	I/O	I	P2[0]	
D2	I/O	I	P3[0]	
D3	I/O	I	P3[1]	
D4	I/O	I	P3[3]	
D5	I/O	I	P2[1]	
E1	Input		XRES	Active high external reset with internal pull-down[21]
E2	IOHR	I	P1[6]	
E3	IOHR	I	P1[4]	Optional external clock input (EXT CLK)
E4	IOHR	I	P1[7]	I^2C SCL, SPI SS
E5	IOHR	I	P1[5]	I^2C SDA, SPI MISO
F1	IOHR	I	P1[2]	Driven Shield Output (optional)
F2	IOHR	I	P1[0]	ISSP DATA[22], I^2C SDA, SPI CLK[23]
F3	Power		V_{SS}	Supply ground[24]
F4	IOHR	I	P1[1]	ISSP CLK[22], I^2C SCL, SPI MOSI
F5	IOHR	I	P1[3]	SPI CLK

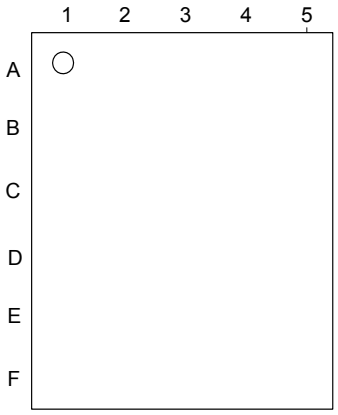
LEGEND: A = Analog, I = Input, O = Output, OH = 5 mA High Output Drive, R = Regulated Output

Figure 5. CY8C20767, CY8C20747 30-ball WLCSP

Bottom View



Top View



Notes

20. 27 GPIOs = 24 pins for capacitive sensing+2 pins for I^2C + 1 pin for modulator capacitor.
21. The internal pull down is 5KOhm.
22. On power-up, the SDA(P1[0]) drives a strong high for 256 sleep clock cycles and drives resistive low for the next 256 sleep clock cycles. The SCL(P1[1]) line drives resistive low for 512 sleep clock cycles and both the pins transition to high impedance state. On reset, after XRES de-asserts, the SDA and the SCL lines drive resistive low for 8 sleep clock cycles and transition to high impedance state. Hence, during power-up or reset event, P1[1] and P1[0] may disturb the I^2C bus. Use alternate pins if you encounter issues.
23. Alternate SPI clock.
24. All VSS pins should be brought out to one common GND plane.

DC Chip-Level Specifications

Table 9 lists guaranteed maximum and minimum specifications for the entire voltage and temperature ranges.

Table 9. DC Chip-Level Specifications

Symbol	Description	Conditions	Min	Typ	Max	Units
V_{DD} [37, 38, 39]	Supply voltage	See Table 14 on page 17.	1.71	–	5.50	V
I_{DD24}	Supply current, IMO = 24 MHz	Conditions are $V_{DD} \leq 3.0$ V, $T_A = 25$ °C, CPU = 24 MHz. CapSense running at 12 MHz, no I/O sourcing current	–	2.88	4.00	mA
I_{DD12}	Supply current, IMO = 12 MHz	Conditions are $V_{DD} \leq 3.0$ V, $T_A = 25$ °C, CPU = 12 MHz. CapSense running at 12 MHz, no I/O sourcing current	–	1.71	2.60	mA
I_{DD6}	Supply current, IMO = 6 MHz	Conditions are $V_{DD} \leq 3.0$ V, $T_A = 25$ °C, CPU = 6 MHz. CapSense running at 6 MHz, no I/O sourcing current	–	1.16	1.80	mA
I_{SB0} [40, 41, 42, 43]	Deep sleep current	$V_{DD} \leq 3.0$ V, $T_A = 25$ °C, I/O regulator turned off	–	0.10	1.1	µA
I_{SB1} [40, 41, 42, 43]	Standby current with POR, LVD and sleep timer	$V_{DD} \leq 3.0$ V, $T_A = 25$ °C, I/O regulator turned off	–	1.07	1.50	µA
I_{SBI2C} [40, 41, 42, 43]	Standby current with I^2C enabled	Conditions are $V_{DD} = 3.3$ V, $T_A = 25$ °C and CPU = 24 MHz	–	1.64	–	µA

Notes

37. When V_{DD} remains in the range from 1.71 V to 1.9 V for more than 50 µs, the slew rate when moving from the 1.71 V to 1.9 V range to greater than 2 V must be slower than 1 V/500 µs to avoid triggering POR. The only other restriction on slew rates for any other voltage range or transition is the SR_{POWER_UP} parameter.
38. If powering down in standby sleep mode, to properly detect and recover from a V_{DD} brown out condition any of the following actions must be taken:
    a. Bring the device out of sleep before powering down.
    b. Assure that V_{DD} falls below 100 mV before powering back up.
    c. Set the No Buzz bit in the OSC_CR0 register to keep the voltage monitoring circuit powered during sleep.
    d. Increase the buzz rate to assure that the falling edge of V_{DD} is captured. The rate is configured through the PSSDC bits in the SLP_CFG register. For the referenced registers, refer to the Technical Reference Manual. In deep sleep/standby sleep mode, additional low power voltage monitoring circuitry allows V_{DD} brown out conditions to be detected and resets the device when V_{DD} goes lower than 1.1 V at edge rates slower than 1 V/ms.
39. For proper CapSense block functionality, if the drop in V_{DD} exceeds 5% of the base V_{DD}, the rate at which V_{DD} drops should not exceed 200 mV/s. Base V_{DD} can be between 1.8 V and 5.5 V.
40. Errata: When programmable timer 0 is used in “one-shot” mode by setting bit 1 of register 0,B0h (PT0_CFG), and the timer interrupt is used to wake the device from sleep, the interrupt service routine (ISR) may be executed twice. For more information, see the “Errata” on page 37.
41. Errata: When in sleep mode, if a GPIO interrupt happens simultaneously with a Timer0 or Sleep Timer interrupt, the GPIO interrupt may be missed, and the corresponding GPIO ISR not run. For more information, see the “Errata” on page 37.
42. Errata: If an interrupt is posted a short time (within 2.5 CPU cycles) before firmware commands the device to sleep, the interrupt will be missed. For more information, see the “Errata” on page 37.
43. Errata: Device wakes up from sleep when an analog interrupt is trigger. For more information, see the “Errata” on page 37.

DC GPIO Specifications

The following tables list guaranteed maximum and minimum specifications for the voltage and temperature ranges: 3.0 V to 5.5 V and –40 °C ≤ T_A ≤ 85 °C, 2.4 V to 3.0 V and –40 °C ≤ T_A ≤ 85 °C, or 1.71 V to 2.4 V and –40 °C ≤ T_A ≤ 85 °C, respectively. Typical parameters apply to 5 V and 3.3 V at 25 °C and are for design guidance only.

Table 10. 3.0 V to 5.5 V DC GPIO Specifications

Symbol	Description	Conditions	Min	Typ	Max	Units
R_{PU}	Pull-up resistor	–	4	5.60	8	kΩ
V_{OH1}	High output voltage Port 2 or 3 pins	I_{OH} ≤ 10 µA, maximum of 10 mA source current in all I/Os	V_{DD} – 0.20	–	–	V
V_{OH2}	High output voltage Port 2 or 3 Pins	I_{OH} = 1 mA, maximum of 20 mA source current in all I/Os	V_{DD} – 0.90	–	–	V
V_{OH3}	High output voltage Port 0 or 1 pins with LDO regulator Disabled for port 1	I_{OH} < 10 µA, maximum of 10 mA source current in all I/Os	V_{DD} – 0.20	–	–	V
V_{OH4}	High output voltage Port 0 or 1 pins with LDO regulator Disabled for port 1	I_{OH} = 5 mA, maximum of 20 mA source current in all I/Os	V_{DD} – 0.90	–	–	V
V_{OH5}	High output voltage Port 1 Pins with LDO Regulator Enabled for 3 V out	I_{OH} < 10 µA, V_{DD} > 3.1 V, maximum of 4 I/Os all sourcing 5 mA	2.85	3.00	3.30	V
V_{OH6}	High output voltage Port 1 pins with LDO regulator enabled for 3 V out	I_{OH} = 5 mA, V_{DD} > 3.1 V, maximum of 20 mA source current in all I/Os	2.20	–	–	V
V_{OH7}	High output voltage Port 1 pins with LDO enabled for 2.5 V out	I_{OH} < 10 µA, V_{DD} > 2.7 V, maximum of 20 mA source current in all I/Os	2.35	2.50	2.75	V
V_{OH8}	High output voltage Port 1 pins with LDO enabled for 2.5 V out	I_{OH} = 2 mA, V_{DD} > 2.7 V, maximum of 20 mA source current in all I/Os	1.90	–	–	V
V_{OH9}	High output voltage Port 1 pins with LDO enabled for 1.8 V out	I_{OH} < 10 µA, V_{DD} > 2.7 V, maximum of 20 mA source current in all I/Os	1.60	1.80	2.10	V
V_{OH10}	High output voltage Port 1 pins with LDO enabled for 1.8 V out	I_{OH} = 1 mA, V_{DD} > 2.7 V, maximum of 20 mA source current in all I/Os	1.20	–	–	V
V_{OL}	Low output voltage	I_{OL} = 25 mA, V_{DD} > 3.3 V, maximum of 60 mA sink current on even port pins (for example, P0[2] and P1[4]) and 60 mA sink current on odd port pins (for example, P0[3] and P1[5])	–	–	0.75	V
V_{IL}	Input low voltage	–	–	–	0.80	V
V_{IH}	Input high voltage	–	V_{DD} × 0.65	–	V_{DD} + 0.7	V
V_H	Input hysteresis voltage	–	–	80	–	mV
I_{IL}	Input leakage (Absolute Value)	–	–	0.001	1	µA
C_{PIN}	Pin capacitance	Package and pin dependent Temp = 25 °C	0.50	1.70	7	pF
$V_{ILLVT3.3}$	Input Low Voltage with low threshold enable set, Enable for Port1 [44]	Bit3 of IO_CFG1 set to enable low threshold voltage of Port1 input	0.8	V	–	–
$V_{IHLVT3.3}$	Input High Voltage with low threshold enable set, Enable for Port1	Bit3 of IO_CFG1 set to enable low threshold voltage of Port1 input	1.4	–	–	V
$V_{ILLVT5.5}$	Input Low Voltage with low threshold enable set, Enable for Port1	Bit3 of IO_CFG1 set to enable low threshold voltage of Port1 input	0.8	V	–	–
$V_{IHLVT5.5}$	Input High Voltage with low threshold enable set, Enable for Port1	Bit3 of IO_CFG1 set to enable low threshold voltage of Port1 input	1.7	–	–	V

Note

44. Errata: Pull-up resistor on port1 pins cannot be connected to a voltage that is greater than 0.7 V higher than CY8C20xx7/S VDD. For more information see item #7 in "Errata" on page 37.

Table 11. 2.4 V to 3.0 V DC GPIO Specifications

Symbol	Description	Conditions	Min	Typ	Max	Units
R_{PU}	Pull-up resistor	–	4	5.60	8	kΩ
V_{OH1}	High output voltage Port 2 or 3 pins	I_{OH} < 10 µA, maximum of 10 mA source current in all I/Os	V_{DD} - 0.20	–	–	V
V_{OH2}	High output voltage Port 2 or 3 Pins	I_{OH} = 0.2 mA, maximum of 10 mA source current in all I/Os	V_{DD} - 0.40	–	–	V
V_{OH3}	High output voltage Port 0 or 1 pins with LDO regulator Disabled for port 1	I_{OH} < 10 µA, maximum of 10 mA source current in all I/Os	V_{DD} - 0.20	–	–	V
V_{OH4}	High output voltage Port 0 or 1 pins with LDO regulator Disabled for Port 1	I_{OH} = 2 mA, maximum of 10 mA source current in all I/Os	V_{DD} - 0.50	–	–	V
V_{OH5A}	High output voltage Port 1 pins with LDO enabled for 1.8 V out	I_{OH} < 10 µA, V_{DD} > 2.4 V, maximum of 20 mA source current in all I/Os	1.50	1.80	2.10	V
V_{OH6A}	High output voltage Port 1 pins with LDO enabled for 1.8 V out	I_{OH} = 1 mA, V_{DD} > 2.4 V, maximum of 20 mA source current in all I/Os	1.20	–	–	V
V_{OL}	Low output voltage	I_{OL} = 10 mA, maximum of 30 mA sink current on even port pins (for example, P0[2] and P1[4]) and 30 mA sink current on odd port pins (for example, P0[3] and P1[5])	–	–	0.75	V
V_{IL}	Input low voltage	–	–	–	0.72	V
V_{IH}	Input high voltage	–	V_{DD} × 0.65	–	V_{DD} + 0.7	V
V_H	Input hysteresis voltage	–	–	80	–	mV
I_{IL}	Input leakage (absolute value)	–	–	1	1000	nA
C_{PIN}	Capacitive load on pins	Package and pin dependent Temp = 25 °C	0.50	1.70	7	pF
$V_{ILLVT2.5}$	Input Low Voltage with low threshold enable set, Enable for Port1	Bit3 of IO_CFG1 set to enable low threshold voltage of Port1 input	0.7	V	–	
$V_{IHLVT2.5}$	Input High Voltage with low threshold enable set, Enable for Port1	Bit3 of IO_CFG1 set to enable low threshold voltage of Port1 input	1.2		–	V

Table 12. 1.71 V to 2.4 V DC GPIO Specifications

Symbol	Description	Conditions	Min	Typ	Max	Units
R_{PU}	Pull-up resistor	–	4	5.60	8	kΩ
V_{OH1}	High output voltage Port 2 or 3 pins	I_{OH} = 10 µA, maximum of 10 mA source current in all I/Os	V_{DD} – 0.20	–	–	V
V_{OH2}	High output voltage Port 2 or 3 pins	I_{OH} = 0.5 mA, maximum of 10 mA source current in all I/Os	V_{DD} – 0.50	–	–	V
V_{OH3}	High output voltage Port 0 or 1 pins with LDO regulator Disabled for Port 1	I_{OH} = 100 µA, maximum of 10 mA source current in all I/Os	V_{DD} – 0.20	–	–	V
V_{OH4}	High output voltage Port 0 or 1 Pins with LDO Regulator Disabled for Port 1	I_{OH} = 2 mA, maximum of 10 mA source current in all I/Os	V_{DD} – 0.50	–	–	V

Table 12. 1.71 V to 2.4 V DC GPIO Specifications *(continued)*

Symbol	Description	Conditions	Min	Typ	Max	Units
V_{OL}	Low output voltage	I_{OL} = 5 mA, maximum of 20 mA sink current on even port pins (for example, P0[2] and P1[4]) and 30 mA sink current on odd port pins (for example, P0[3] and P1[5])	–	–	0.40	V
V_{IL}	Input low voltage	–	–	–	0.30 × V_{DD}	V
V_{IH}	Input high voltage	–	0.65 × V_{DD}	–	–	V
V_H	Input hysteresis voltage	–	–	80	–	mV
I_{IL}	Input leakage (absolute value)	–	–	1	1000	nA
C_{PIN}	Capacitive load on pins	Package and pin dependent temp = 25 °C	0.50	1.70	7	pF

Table 13. GPIO Current Sink and Source Specifications

Supply Voltage	Mode	Port 0/1 per I/O (max)	Port 2/3/4 per I/O (max)	Total Current Even Pins (max)	Total Current Odd Pins (max)	Units
1.71–2.4	Sink	5	5	20	30	mA
	Source	2	0.5	10[45]		mA
2.4–3.0	Sink	10	10	30	30	mA
	Source	2	0.2	10[45]		mA
3.0–5.0	Sink	25	25	60	60	mA
	Source	5	1	20[45]		mA

DC Analog Mux Bus Specifications

Table 14 lists guaranteed maximum and minimum specifications for the entire voltage and temperature ranges.

Table 14. DC Analog Mux Bus Specifications

Symbol	Description	Conditions	Min	Typ	Max	Units
R_{SW}	Switch resistance to common analog bus	–	–	–	800	Ω
R_{GND}	Resistance of initialization switch to V_{SS}	–	–	–	800	Ω

The maximum pin voltage for measuring R_{SW} and R_{GND} is 1.8 V

DC Low Power Comparator Specifications

Table 15 lists guaranteed maximum and minimum specifications for the entire voltage and temperature ranges.

Table 15. DC Comparator Specifications

Symbol	Description	Conditions	Min	Typ	Max	Units
V_{LPC}	Low power comparator (LPC) common mode	Maximum voltage limited to V_{DD}	0.2	–	1.8	V
I_{LPC}	LPC supply current	–	–	10	80	µA
V_{OSLPC}	LPC voltage offset	–	–	2.5	30	mV

Note
45. Total current (odd + even ports)

Comparator User Module Electrical Specifications

Table 16 lists the guaranteed maximum and minimum specifications. Unless stated otherwise, the specifications are for the entire device voltage and temperature operating range: –40 °C ≤ TA ≤ 85 °C, 1.71 V ≤ V_{DD} ≤ 5.5 V.

Table 16. Comparator User Module Electrical Specifications

Symbol	Description	Conditions	Min	Typ	Max	Units
T_{COMP}	Comparator response time	50 mV overdrive	–	70	100	ns
Offset	–	Valid from 0.2 V to 1.5 V	–	2.5	30	mV
Current	–	Average DC current, 50 mV overdrive	–	20	80	µA
PSRR	Supply voltage > 2 V	Power supply rejection ratio	–	80	–	dB
	Supply voltage < 2 V	Power supply rejection ratio	–	40	–	dB
Input range	–	–	0.2		1.5	V

ADC Electrical Specifications

Table 17. ADC User Module Electrical Specifications

Symbol	Description	Conditions	Min	Typ	Max	Units
Input						
V_{IN}	Input voltage range	–	0	–	VREFADC	V
C_{IIN}	Input capacitance	–	–	–	5	pF
R_{IN}	Input resistance	Equivalent switched cap input resistance for 8-, 9-, or 10-bit resolution	1/(500fF × data clock)	1/(400fF × data clock)	1/(300fF × data clock)	Ω
Reference						
V_{REFADC}	ADC reference voltage	–	1.14	–	1.26	V
Conversion Rate						
F_{CLK}	Data clock	Source is chip's internal main oscillator. See AC Chip-Level Specifications on page 21 for accuracy	2.25	–	6	MHz
S8	8-bit sample rate	Data clock set to 6 MHz. sample rate = 0.001/ (2^Resolution/Data Clock)	–	23.43	–	ksps
S10	10-bit sample rate	Data clock set to 6 MHz. sample rate = 0.001/ (2^resolution/data clock)	–	5.85	–	ksps
DC Accuracy						
RES	Resolution	Can be set to 8, 9, or 10 bit	8	–	10	bits
DNL	Differential nonlinearity	–	–1	–	+2	LSB
INL	Integral nonlinearity	–	–2	–	+2	LSB
E_{OFFSET}	Offset error	8-bit resolution	0	3.20	19.20	LSB
		10-bit resolution	0	12.80	76.80	LSB
E_{GAIN}	Gain error	For any resolution	–5	–	+5	%FSR
Power						
I_{ADC}	Operating current	–	–	2.10	2.60	mA
PSRR	Power supply rejection ratio	PSRR (V_{DD} > 3.0 V)	–	24	–	dB
		PSRR (V_{DD} < 3.0 V)	–	30	–	dB

AC Chip-Level Specifications

Table 24 lists guaranteed maximum and minimum specifications for the entire voltage and temperature ranges.

Table 24. AC Chip-Level Specifications

Symbol	Description	Conditions	Min	Typ	Max	Units
F_{IMO24}	IMO frequency at 24 MHz Setting	–	22.8	24	25.2	MHz
F_{IMO12}	IMO frequency at 12 MHz setting	–	11.4	12	12.6	MHz
F_{IMO6}	IMO frequency at 6 MHz setting	–	5.7	6.0	6.3	MHz
F_{CPU}	CPU frequency	–	0.75	–	25.20	MHz
F_{32K1}	ILO frequency	–	15	32	50	kHz
F_{32K_U}	ILO untrimmed frequency	–	–	32	–	kHz
DC_{IMO}	Duty cycle of IMO	–	40	50	60	%
DC_{ILO}	ILO duty cycle	–	40	50	60	%
SR_{POWER_UP}	Power supply slew rate	V_{DD} slew rate during power-up	–	–	250	V/ms
t_{XRST}	External reset pulse width at power-up	After supply voltage is valid	1	–	–	ms
t_{XRST2}	External reset pulse width after power-up[52]	Applies after part has booted	10	–	–	µs
t_{JIT_IMO}[53]	6 MHz IMO cycle-to-cycle jitter (RMS)	–	–	0.7	6.7	ns
	6 MHz IMO long term N cycle-to-cycle jitter (RMS); N = 32	–	–	4.3	29.3	ns
	6 MHz IMO period jitter (RMS)	–	–	0.7	3.3	ns
	12 MHz IMO cycle-to-cycle jitter (RMS)	–	–	0.5	5.2	ns
	12 MHz IMO long term N cycle-to-cycle jitter (RMS); N = 32	–	—	2.3	5.6	ns
	12 MHz IMO period jitter (RMS)	–	–	0.4	2.6	ns
	24 MHz IMO cycle-to-cycle jitter (RMS)	–	–	1.0	8.7	ns
	24 MHz IMO long term N cycle-to-cycle jitter (RMS); N = 32	–	–	1.4	6.0	ns
	24 MHz IMO period jitter (RMS)	–	–	0.6	4.0	ns

Note
52. The minimum required XRES pulse length is longer when programming the device (see Table 28 on page 23).
53. See the Cypress Jitter Specifications application note, Understanding Datasheet Jitter Specifications for Cypress Timing Products – AN5054 for more information.

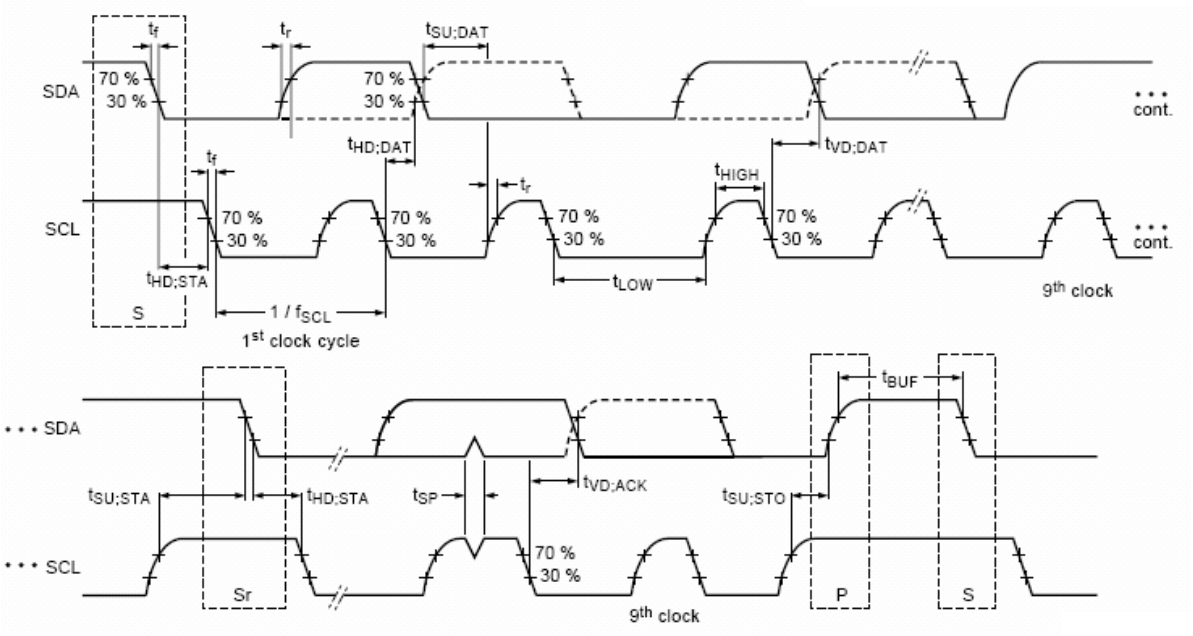
AC I²C Specifications

Table 29 lists guaranteed maximum and minimum specifications for the entire voltage and temperature ranges.

Table 29. AC Characteristics of the I²C SDA and SCL Pins

Symbol	Description	Standard Mode		Fast Mode		Units
		Min	Max	Min	Max	
f_{SCL}	SCL clock frequency	0	100	0	400	kHz
$t_{HD;STA}$	Hold time (repeated) START condition. After this period, the first clock pulse is generated	4.0	–	0.6	–	µs
t_{LOW}	LOW period of the SCL clock	4.7	–	1.3	–	µs
t_{HIGH}	HIGH Period of the SCL clock	4.0	–	0.6	–	µs
$t_{SU;STA}$	Setup time for a repeated START condition	4.7	–	0.6	–	µs
$t_{HD;DAT}$[55]	Data hold time	20	3.45	20	0.90	µs
$t_{SU;DAT}$	Data setup time	250	–	100[56]	–	ns
$t_{SU;STO}$	Setup time for STOP condition	4.0	–	0.6	–	µs
t_{BUF}	Bus free time between a STOP and START condition	4.7	–	1.3	–	µs
t_{SP}	Pulse width of spikes are suppressed by the input filter	–	–	0	50	ns

Figure 11. Definition for Timing for Fast/Standard Mode on the I²C Bus



Notes

55. Errata: To wake up from sleep using I2C hardware address match event, I2C interface needs 20 ns hold time on SDA line with respect to falling edge of SCL. For more information see item #5 in the "Errata" on page 37.
56. A Fast-Mode I²C-bus device can be used in a standard mode I²C-bus system, but the requirement $t_{SU;DAT} \geq 250$ ns must then be met. This automatically be the case if the device does not stretch the LOW period of the SCL signal. If such device does stretch the LOW period of the SCL signal, it must output the next data bit to the SDA line $t_{rmax} + t_{SU;DAT} = 1000 + 250 = 1250$ ns (according to the Standard-Mode I²C-bus specification) before the SCL line is released.

Table 30. SPI Master AC Specifications

Symbol	Description	Conditions	Min	Typ	Max	Units
F_{SCLK}	SCLK clock frequency	$V_{DD} \geq 2.4$ V $V_{DD} < 2.4$ V	– –	– –	6 3	MHz MHz
DC	SCLK duty cycle	–	–	50	–	%
t_{SETUP}	MISO to SCLK setup time	$V_{DD} \geq 2.4$ V $V_{DD} < 2.4$ V	60 100	– –	– –	ns ns
t_{HOLD}	SCLK to MISO hold time	–	40	–	–	ns
t_{OUT_VAL}	SCLK to MOSI valid time	–	–	–	40	ns
t_{OUT_H}	MOSI high time	–	40	–	–	ns

Figure 12. SPI Master Mode 0 and 2

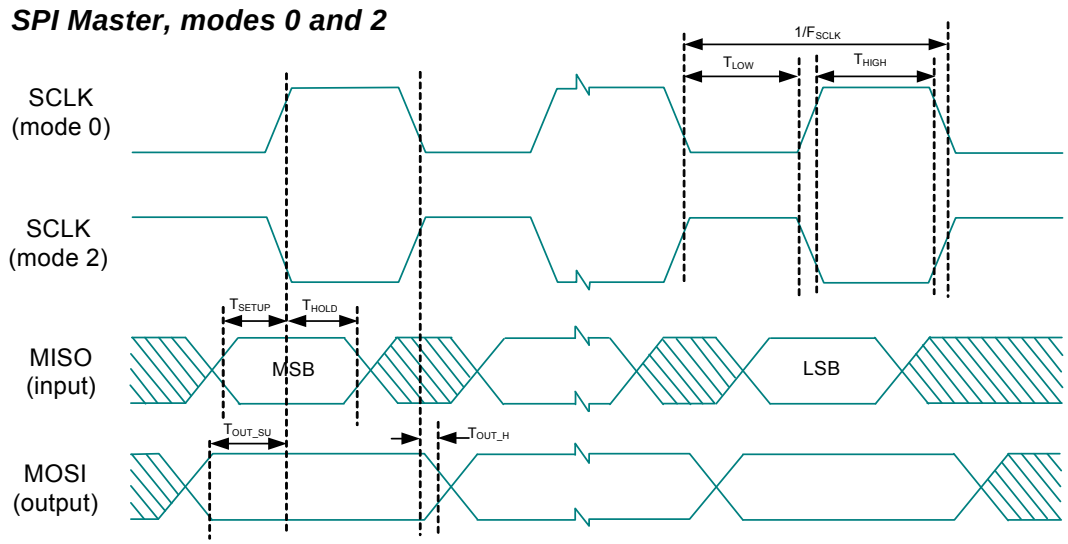
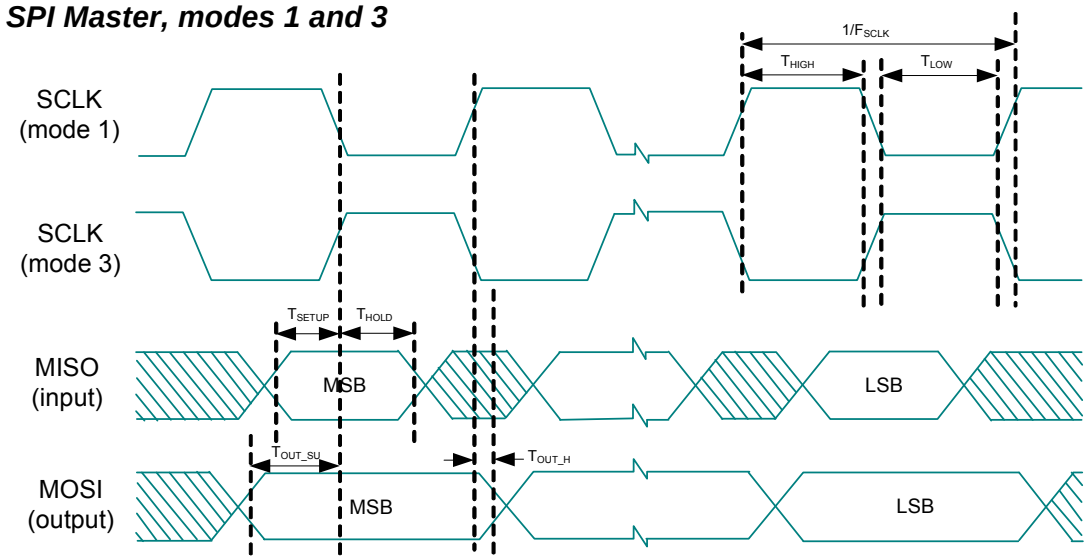


Figure 13. SPI Master Mode 1 and 3



Thermal Impedances

Table 32. Thermal Impedances per Package

Package	Typical θ_{JA} [57]
16-pin SOIC	95 °C/W
16-pin QFN	33 °C/W
24-pin QFN[58]	21 °C/W
32-pin QFN[58]	20 °C/W
48-pin QFN[58]	18 °C/W
30-ball WLCSP	54 °C/W

Capacitance on Crystal Pins

Table 33. Typical Package Capacitance on Crystal Pins

Package	Package Capacitance
32-Pin QFN	3.2 pF
48-Pin QFN	3.3 pF

Solder Reflow Peak Temperature

Table 34 shows the solder reflow temperature limits that must not be exceeded.

Table 34. Solder Reflow Peak Temperature

Package	Maximum Peak Temperature (T_C)	Maximum Time above T_C – 5 °C
16-pin SOIC	260 °C	30 seconds
16-pin QFN	260 °C	30 seconds
24-pin QFN	260 °C	30 seconds
32-pin QFN	260 °C	30 seconds
48-pin QFN	260 °C	30 seconds
30-ball WLCSP	260 °C	30 seconds

Notes
57. $T_J = T_A + \text{Power} \times \theta_{JA}$.
58. To achieve the thermal impedance specified for the QFN package, the center thermal pad must be soldered to the PCB ground plane.

Acronyms

The following table lists the acronyms that are used in this document.

Table 36. Acronyms Used in this Document

Acronym	Description
AC	alternating current
ADC	analog-to-digital converter
API	application programming interface
CMOS	complementary metal oxide semiconductor
CPU	central processing unit
DAC	digital-to-analog converter
DC	direct current
ESD	electrostatic discharge
FSR	full scale range
GPIO	general purpose input/output
I^2C	inter-integrated circuit
ICE	in-circuit emulator
ILO	internal low speed oscillator
IMO	internal main oscillator
I/O	input/output
ISSP	in-system serial programming
LCD	liquid crystal display
LDO	low dropout (regulator)
LED	light-emitting diode
LPC	low power comparator
LSB	least-significant bit
LVD	low voltage detect
MCU	micro-controller unit
MIPS	million instructions per second
MISO	master in slave out
MOSI	master out slave in
MSB	most-significant bit
OCD	on-chip debug
PCB	printed circuit board
POR	power on reset
PSRR	power supply rejection ratio
PWRSYS	power system
PSoC	programmable system-on-chip
QFN	quad flat no-lead
SCLK	serial I^2C clock
SDA	serial I^2C data
SDATA	serial ISSP data
SOIC	small outline integrated circuit
SPI	serial peripheral interface
SRAM	static random access memory
SS	slave select
USB	universal serial bus
WLCSP	wafer level chip scale package

Reference Documents

- *Technical reference manual for CY20xx7 devices*
- *In-system Serial Programming (ISSP) protocol for 20xx7*
- *Host Sourced Serial Programming for 20xx7 devices*

Document Conventions

Units of Measure

Table 37 lists all the abbreviations used to measure the PSoC devices.

Table 37. Units of Measure

Symbol	Unit of Measure
°C	degree Celsius
dB	decibel
kHz	kilohertz
ksps	kilo samples per second
kΩ	kilohm
MHz	megahertz
µA	microampere
µs	microsecond
mA	milliampere
mm	millimeter
ms	millisecond
mV	millivolt
nA	nanoampere
ns	nanosecond
Ω	ohm
%	percent
pF	picofarad
V	volt
W	watt

Numeric Naming

Hexadecimal numbers are represented with all letters in uppercase with an appended lowercase ‘h’ (for example, ‘14h’ or ‘3Ah’). Hexadecimal numbers may also be represented by a ‘0x’ prefix, the C coding convention. Binary numbers have an appended lowercase ‘b’ (for example, 01010100b’ or ‘01000011b’). Numbers not indicated by an ‘h’, ‘b’, or 0x are decimal.

Glossary

Crosspoint connection	Connection between any GPIO combination via analog multiplexer bus.
Differential non linearity	Ideally, any two adjacent digital codes correspond to output analog voltages that are exactly one LSB apart. Differential non-linearity is a measure of the worst case deviation from the ideal 1 LSB step.
Hold time	Hold time is the time following a clock event during which the data input to a latch or flip-flop must remain stable in order to guarantee that the latched data is correct.
I^2C	It is a serial multi-master bus used to connect low speed peripherals to MCU.
Integral nonlinearity	It is a term describing the maximum deviation between the ideal output of a DAC/ADC and the actual output level.
Latch-up current	Current at which the latch-up test is conducted according to JESD78 standard (at 125 degree Celsius)
Power supply rejection ratio (PSRR)	The PSRR is defined as the ratio of the change in supply voltage to the corresponding change in output voltage of the device.
Scan	The conversion of all sensor capacitances to digital values.
Setup time	Period required to prepare a device, machine, process, or system for it to be ready to function.
Signal-to-noise ratio	The ratio between a capacitive finger signal and system noise.
SPI	Serial peripheral interface is a synchronous serial data link standard.

3. Missed Interrupt During Transition to Sleep

■Problem Definition

If an interrupt is posted a short time (within 2.5 CPU cycles) before firmware commands the device to sleep, the interrupt will be missed.

■Parameters Affected

No datasheet parameters are affected.

■Trigger Condition(S)

Triggered by enabling sleep mode just prior to an interrupt.

■Scope of Impact

The relevant interrupt service routine will not be run.

■Workaround

None.

■Fix Status

Will not be fixed

■Changes

None

4. Wakeup from sleep with analog interrupt

■Problem Definition

Device wakes up from sleep when an analog interrupt is trigger

■Parameters Affected

No datasheet parameters are affected.

■Trigger Condition(S)

Triggered by enabling analog interrupt during sleep mode when device operating temperature is 50 °C or above

■Scope of Impact

Device unexpectedly wakes up from sleep

■Workaround

Disable the analog interrupt before entering sleep and turn it back on upon wake-up.

■Fix Status

Will not be fixed

■Changes

None

5. Wake-up from Sleep with Hardware I2C Address match on Pins P1[0], P1[1]

■Problem Definition

I2C interface needs 20 ns hold time on SDA line with respect to falling edge of SCL, to wake-up from sleep using I2C hardware address match event.

■Parameters Affected

$t_{HD;DAT}$ increased to 20 ns from 0 ns

■Trigger Condition(S)

This is an issue only when all these three conditions are met:

1) P1.0 and P1.1 are used as I2C pins,

2) Wakeup from sleep with hardware address match feature is enabled, and

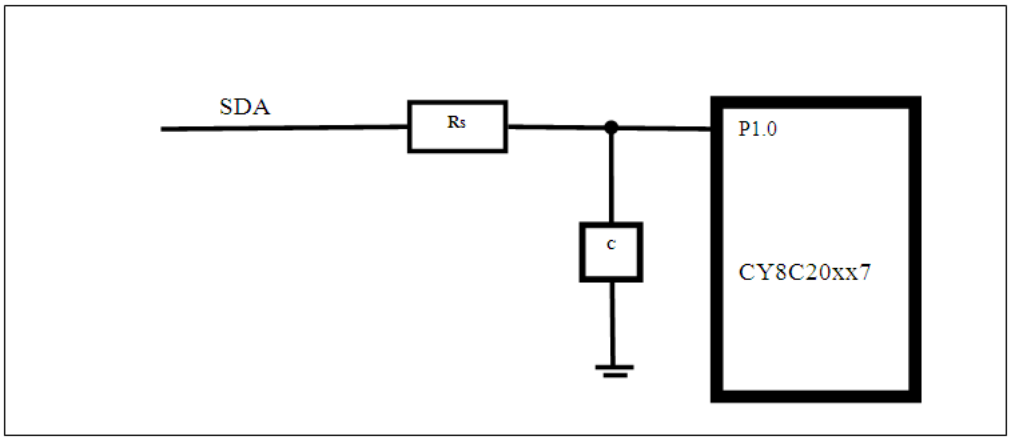
3) I2C master does not provide 20 ns hold time on SDA with respect to falling edge of SCL.

■Scope of Impact

These trigger conditions cause the device to never wake-up from sleep based on I2C address match event.

■Workaround

For a design that meets all of the trigger conditions, the following suggested circuit has to be implemented as a work-around. The R and C values proposed are 100 ohm and 200 pF respectively.



■Fix Status

Will not be fixed

■Changes

None

Document History Page

Document Title: CY8C20xx7/S, 1.8 V CapSense® Controller with SmartSense™ Auto-tuning 31 Buttons, 6 Sliders, Proximity Sensors Document Number: 001-69257				
Revision	**ECN**	**Orig. of Change**	**Submission Date**	**Description of Change**
**	3276782	DST	06/27/2011	New silicon and document
*A	3327230	DST	07/28/2011	Changed 48-pin dimensions to 6 × 6 × 0.6 mm QFN Updated pins name in Table 3 on page 9 and removed USB column and updated dimensions for 48-pin parts in Table 35 on page 33 Updated Figure 20 on page 29 Removed ICE and Debugger sections. Removed CY3215 Development Kit and CY3280-20x66 UCC sections. Updated Ordering Information.
*B	3403111	YVA	10/12/2011	Moved status from Advance to Preliminary. Updated Ordering Information Removed the row named “48-Pin (6 × 6 mm) QFN (OCD)”. Changed all 48-pin ordering code column from CY8C20XXX-24LTxx to CY8C20XXX-24LQxx. Updated 16-pin SOIC and 16-pin QFN package drawings.
*C	3473317	DST	12/23/2011	Updated Features. Updated Pinouts (Removed PSoC in captions of Figure 2, Figure 3, Figure 4, Figure 6, and Figure 7). Updated DC Chip-Level Specifications under Electrical Specifications (Updated typical value of I_{DD24} parameter from 3.32 mA to 2.88 mA, updated typical value of I_{DD12} parameter from 1.86 mA to 1.71 mA, updated typical value of I_{DD6} parameter from 1.13 mA to 1.16 mA, updated maximum value of I_{SB0} parameter from 0.50 µA to 1.1 µA, added I_{SBI2C} parameter and its details). Updated DC GPIO Specifications under Electrical Specifications (Added the parameters namely $V_{ILLVT3.3}$, $V_{IHLVT3.3}$, $V_{ILLVT5.5}$, $V_{IHLVT5.5}$ and their details in Table 10, added the parameters namely $V_{ILLVT2.5}$, $V_{IHLVT2.5}$ and their details in Table 11). Added the following sections namely DC I2C Specifications, Shield Driver DC Specifications, and DC IDAC Specifications under Electrical Specifications. Updated AC Chip-Level Specifications (Added the parameter namely t_{JIT_IMO} and its details). Updated Ordering Information (updated Table 35).
*D	3510277	YVA/DST	02/16/2012	Added CY8C20x37/37S/47/47S/67/67S part numbers and changed title to “1.8 V CapSense® Controller with SmartSense™ Auto-tuning 31 Buttons, 6 Sliders” Updated Features. Modified comparator blocks in Logic Block Diagram. Replaced SmartSense with SmartSense auto-tuning. Added CY8C20xx7S part numbers in Pin Definitions. Added footnote for Table 20. Updated Table 21 and Table 22 and added Table 23. Updated F_{32K1} min value. Updated data hold time min values. Updated CY8C206x7 part information in Table “Emulation and Programming Accessories”. Updated Ordering Information.
*E	3539259	DST	03/01/2012	Changed Datasheet status from Preliminary to Final. Updated all Pinouts to include Driven Shield Output (optional) information. Updated Min value for V_{LPC} Table 15. Updated Offset and Input range in Table 16.

Document History Page *(continued)*

Document Title: CY8C20xx7/S, 1.8 V CapSense® Controller with SmartSense™ Auto-tuning 31 Buttons, 6 Sliders, Proximity Sensors Document Number: 001-69257				
Revision	**ECN**	**Orig. of Change**	**Submission Date**	**Description of Change**
*F	3645807	DST/BVI	07/03/2012	Updated F_{SCLK} parameter in the Table 31, “SPI Slave AC Specifications,” on page 26 Changed t_{OUT_HIGH} to t_{OUT_H} in Table 30, “SPI Master AC Specifications,” on page 25 Updated Features section, “Programmable pin configurations” bullet: ■ Included the following sub-bullet point - 5 mA source current on port 0 and 1 and 1 mA on port 2,3 and 4 ■ Changed the bullet point “High sink current of 25 mA for each GPIO” to “High sink current of 25 mA for each GPIO. Total 120 mA maximum sink current per chip” ■ Added “QuietZone™ Controller” bullet and updated “Low power CapSense® block with SmartSense™ auto-tuning” bullet. Updated package diagrams 001-13937 to *D and 001-57280 to *C revisions.
*G	3800055	DST	11/23/2012	Changed document title. Part named changed from CY8C20xx7 to CY8C20xx7/S Table 20: Update to VIHI2C to match Item #6 in K2 Si Errata document (001-75370) Updated package diagrams: 51-85068 to *E 001-09116 to *G 001-13937 to *E 001-42168 to *E 001-57280 to *E
*H	3881332	SRLI	02/04/2013	Updated Features: Added Note “Please contact your nearest sales office for additional details.” and referred the same note in “24 Sensing Inputs – 30-pin WLCSP”.
*I	3993458	DST	05/07/2013	Updated Electrical Specifications (Updated DC GPIO Specifications (Updated heading of third column as “Port 0/1 per I/O (max)” for Table 13)). Updated Packaging Information: spec 001-09116 – Changed revision from *G to *H (Figure 17). Added Errata.
*J	4081796	DST	07/31/2013	Added Errata footnotes (Note 40, 41, 42, 43, 44). Updated already existing footnotes (Note 50, 51, 55) as Errata footnotes. Updated Electrical Specifications: Updated DC Chip-Level Specifications: Added Note 40, 41, 42, 43 and referred the same notes in I_{SB0}, I_{SB1}, I_{SBI2C} parameters. Updated DC GPIO Specifications: Added Note 44 and referred the same note in description of $V_{ILLVT3.3}$ parameter in Table 10. Updated DC I2C Specifications: Updated Note 50, 51 referred in Table 20. Updated AC I2C Specifications: Updated Note 55 referred in Table 29. Updated to new template.